

### SLOVENSKI STANDARD SIST EN IEC 61280-4-3:2022

01-november-2022

Postopki preskušanja optičnega komunikacijskega podsistema - 4-3. del: Vgrajena pasivna optična omrežja - Meritve slabljenja in optičnih povratnih izgub (IEC 61280 -4-3:2022)

Fibre-optic communication subsystem test procedures - Part 4-3: Installed passive optical networks - Attenuation and optical return loss measurements (IEC 61280-4-3:2022)

Prüfverfahren für Lichtwellenleiter-Kommunikationsuntersysteme - Teil 4-3: Installierte passive optische Netze - Messung von Dämpfung und optischer Rückflussdämpfung (IEC 61280-4-3:2022)

Procédures d'essai des sous-systèmes de télécommunications fibroniques - Partie 4-3: Installations de réseau optique passif - Mesures de l'affaiblissement et de l'affaiblissement de réflexion optique (IEC 61280-4-3:2022)

Ta slovenski standard je istoveten z: EN IEC 61280-4-3:2022

ICS:

33.180.01 Sistemi z optičnimi vlakni na Fibre optic systems in splošno

general

SIST EN IEC 61280-4-3:2022 en SIST EN IEC 61280-4-3:2022

# iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST EN IEC 61280-4-3:2022

https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sisten-iec-61280-4-3-2022

EUROPEAN STANDARD NORME EUROPÉENNE FUROPÄISCHE NORM EN IEC 61280-4-3

September 2022

ICS 33.180.01

### **English Version**

Fibre optic communication subsystem test procedures - Part 4-3: Installed passive optical networks - Attenuation and optical return loss measurements (IEC 61280-4-3:2022)

Procédures d'essai des sous-systèmes de télécommunications fibroniques - Partie 4-3: Installations de réseau optique passif - Mesures de l'affaiblissement et de l'affaiblissement de réflexion optique (IEC 61280-4-3:2022) Prüfverfahren für Lichtwellenleiter-Kommunikationsuntersysteme - Teil 4-3: Installierte passive optische Netze - Messung von Dämpfung und optischer Rückflussdämpfung (IEC 61280-4-3:2022)

This European Standard was approved by CENELEC on 2022-09-02. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sist-

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Republic of North Macedonia, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Türkiye and the United Kingdom.



European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 61280-4-3:2022 (E)

### **European foreword**

The text of document 86C/1749A/CDV, future edition 1 of IEC 61280-4-3, prepared by SC 86C "Fibre optic systems and active devices" of IEC/TC 86 "Fibre optics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61280-4-3:2022.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2023-06-02 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2025-09-02 document have to be withdrawn

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

### **Endorsement notice**

The text of the International Standard IEC 61280-4-3:2022 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60875-1:2015 NOTE Harmonized as EN 60875-1:2015 (not modified)

IEC 61280-1-1 NOTE Harmonized as EN 61280-1-1

IEC 61746-2 NOTE Harmonized as EN 61746-2

IEC 61755-3-1<sup>1</sup> NOTE Harmonized as EN 61755-3-1<sup>2</sup>

IEC 61755-3-2<sup>3</sup> NOTE Harmonized as EN 61755-3-2<sup>4</sup>

IEC 62074-1:2014 NOTE Harmonized as EN 62074-1:2014 (not modified)

-

<sup>&</sup>lt;sup>1</sup> Under preparation. Stage at the time of publication: IEC 61755-3-1/CD:2022.

<sup>&</sup>lt;sup>2</sup> Under preparation. Stage at the time of publication: prEN IEC 61755-3-1:2020.

<sup>&</sup>lt;sup>3</sup> Under preparation. Stage at the time of publication: IEC 61755-3-2/CD:2022.

<sup>&</sup>lt;sup>4</sup> Under preparation. Stage at the time of publication: prEN IEC 61755-3-2:2020.

EN IEC 61280-4-3:2022 (E)

## Annex ZA (normative)

## Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60793-2-50	-	Optical fibres - Part 2-50: Product specifications - Sectional specification for class B single-mode fibres	EN IEC 60793-2-50	) -
IEC 61280-1-3	Teh	Fibre optic communication subsystem test procedures - Part 1-3: General communication subsystems - Measurement of central wavelength, spectral width and additional spectral characteristics	EN IEC 61280-1-3	-
IEC 61280-4-2	s.i <del>t</del> eh.ai∕o	Fibre-optic communication subsystem test procedures - Part 4-2: Installed cable plant - Single-mode attenuation and optical return loss measurement		ta4/sist-
IEC/TR 61282-14	2019	Fibre optic communication system design guidelines - Part 14: Determination of the uncertainties of attenuation measurements in fibre plants		-
IEC 61300-3-35	-	Fibre optic interconnecting devices and passive components - Basic test and measurement procedures - Part 3-35: Examinations and measurements - Visual inspection of fibre optic connectors and fibre-stub transceivers	EN 61300-3-35	-
IEC 61315	-	Calibration of fibre-optic power meters	EN IEC 61315	-
IEC 61746-1	2009	Calibration of optical time-domain reflectometers (OTDR) - Part 1: OTDR for single mode fibres	EN 61746-1	2011
			+ AC	2014
IEC 61753-031-2	-	Fibre optic interconnecting devices and passive components - Performance standard - Part 031-2: Non-connectorized single-mode 1 × N and 2 × N non-wavelength-selective branching devices fo Category C - Controlled environment	EN 61753-031-2 r	-

### EN IEC 61280-4-3:2022 (E)

IEC 61753-031-3 -	Fibre optic interconnecting devices and passive components - Performance standard - Part 031-3: Non-connectorized single-mode 1×N and 2×N non-wavelength-selective branching devices for Category U - Uncontrolled environment	EN 61753-031-3	-
IEC 61753-031-6 -	Fibre optic interconnecting devices and passive components - Performance standard - Part 031-6: Non-connectorized single-mode 1×N and 2×N non-wavelength-selective branching devices for Category O - Uncontrolled environment	EN 61753-031-6	-
IEC 61753-1 -	Fibre optic interconnecting devices and passive components - Performance standard - Part 1: General and guidance	EN IEC 61753-1	-
IEC/TR 62627-01 -	Fibre optic interconnecting devices and passive components - Part 01: Fibre optic connector cleaning methods	-	-

# iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>SIST EN IEC 61280-4-3:2022</u> https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sist en-iec-61280-4-3-2022



IEC 61280-4-3

Edition 1.0 2022-07

## INTERNATIONAL STANDARD

## NORME INTERNATIONALE



Part 4-3: Installed passive optical networks – Attenuation and optical return loss measurements

Procédures d'essai des sous-systèmes de télécommunications fibroniques – Partie 4-3: Installations de réseau optique passif – Mesures de l'affaiblissement et de l'affaiblissement de réflexion optique

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

ICS 33.180.01 ISBN 978-2-8322-4801-0

Warning! Make sure that you obtained this publication from an authorized distributor.

Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.

### CONTENTS

F	DREWO	RD	6
IN	TRODU	CTION	8
1	Scop	e	9
2	Norm	ative references	9
3	Term	s, definitions, and abbreviated terms	10
	3.1	Terms and definitions	10
	3.2	Abbreviated terms	12
4	Basic	PON architecture	13
5	Atten	uation measurement	13
	5.1	General	13
	5.2	Methods	14
	5.3	Cabling configurations	14
	5.4	RTM for attenuation measurement	14
6	Appa	ratus for attenuation measurement	.14
	6.1	General	14
	6.2	Light source	15
	6.2.1	Stability	15
	6.2.2		15
	6.3	Laurich cord	. 15
	6.4	Receive or tail cord	
	6.5	Power meter – LSPM method only	
	6.6	OTDR apparatus	.16
	6.6.1	General	16
	6.6.2	OTDK spectral characteristics	. 10
7	6.7	Connector end face cleaning and inspection equipment	
7		view of uncertainties	
	7.1	General	
	7.2	Typical uncertainty values for method A	
0	7.3	Typical uncertainty values for method Bal return loss measurements	
O	•		
	8.1 8.2	General ORL measurements using CW	
	8.3	Reflectance measurement using an OTDR	
Δr		normative) LSPM one-cord reference method	
/\l	A.1	Applicability of test method	
	A.1 A.2	Apparatus	
	A.3	Procedure	
	A.4	Calculation	
	A.5	Components of reported attenuation	
Ar		normative) Optical time-domain reflectometer method	
-	B.1	Applicability of test method	
	B.2	Apparatus	
	B.2.1	• •	
	B.2.2		
	B.2.3	Test cords	22
	B.3	Procedure (test method)	23

В.4	Calculation of attenuation	24
B.4.1	General	24
B.4.2	Connection location	24
B.4.3	Definition of the power levels $F_1$ and $F_2$	25
B.5	Testing launch and tail cords	
B.5.1	-	
B.5.2		
	(informative) Filtered optical time-domain reflectometer	
C.1	General	
C.1	Applicability of the method	
C.3	Apparatus	
C.3.1	••	
C.3.2		
C.4	Test method	
C.5	Calculation of attenuation	
C.5.1		
C.5.2		
C.5.3		
C.6	Uncertainties	
C.7	Consideration relative to the measurement of an unused branch of the ODN	
C.1	while at least one branch is active	31
C.7.1		
C.7.2		
Annex D	(informative) PON configuration	
D.1	General SIST EN IEC 61280-4-3:2022	
htp://st	Basic configuration	
D.3	Coexistence of different PON systems	
D.4	Wavelength multiplexing	
Annex E (	(informative) Basic uncertainty analysis for methods B and C	
E.1	General	
E.2	Uncertainties due to measuring instrument	
E.3	Uncertainties due to the setup	
E.4	Uncertainties due to cabling	
E.5	Relative uncertainty arising from the uncertainty of the OTDR wavelength	
E.5.1		
E.5.2		
E.6	Relative uncertainty arising from non-linearity of the OTDR	41
E.7	Uncertainty arising from OTDR noise	
E.7.1	General	41
E.7.2	Linear regression	42
E.7.3	Practical determination of uncertainty arising from OTDR noise	44
E.8	Relative uncertainty arising from OTDR cursor placement	47
E.9	Considerations on backscatter coefficient	47
E.10	Sensitivity coefficients	48
E.10	.1 General	48
E.10	,	48
E.10	, , , , , , , , , , , , , , , , , , , ,	
	regression)	
Annex F (	informative) OTDR configuration information	51

F.2.1 Fundamental parameters that define the operational capability of an OTDR. F.2.1 Dynamic range F.2.2 Dynamic margin F.2.3 Pulse width F.2.4 Averaging time F.2.5 Dead zone F.2.6 Distance sampling Bibliography.  Figure 1 – Single stage conventional ODN structure Figure 2 – Cabling configuration – Start and end of measured losses in reference test method Figure 3 – Typical OTDR schematic Figure A.1 – One-cord reference measurement Figure A.2 – One-cord test measurement Figure B.1 – Test measurement for method B Figure B.3 – Graphic determination of F1 and F2 Figure B.3 – Graphic determination of F1 and F2 Figure C.1 – Location of the connector ports of the cabling under test Figure C.2 – Graphic determination of F1 and F2 Figure C.3 – OLT structure and signal wavelengths Figure C.4 – WDM filter response Figure D.1 – Single stage conventional ODN structure Figure D.2 – Multiple stage conventional ODN structure Figure D.3 – Implementation of coexistence PON systems Figure D.4 – Single-stage PIP WDM ODN structure Figure D.5 – Multiple-stage PIP WDM ODN structure Figure D.5 – Multiple-stage PIP WDM ODN structure Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model. Figure E.3 – Spectral attenuation Figure E.3 – Spectral attenuation Figure E.5 – OTDR trace and noise Figure E.6 – Noise asymmetry function of DM Figure E.6 – Noise asymmetry function of DM Figure E.7 – Measurement validity limits Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements Table 2 – OTDR spectral requirements Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors.  Table 5 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using OTDR.	F.1 Ge	eneral	51
F.2.2 Dynamic margin. F.2.3 Pulse width. F.2.4 Averaging time F.2.5 Dead zone. F.2.6 Distance sampling.  Bibliography.  Figure 1 – Single stage conventional ODN structure.  Figure 2 – Cabling configuration – Start and end of measured losses in reference test method.  Figure 3 – Typical OTDR schematic.  Figure A.1 – One-cord reference measurement.  Figure A.2 – One-cord test measurement.  Figure B.3 – Test measurement for method B.  Figure B.3 – Graphic determination of $F_1$ and $F_2$ .  Figure C.1 – Location of the connector ports of the cabling under test.  Figure C.2 – Graphic determination of $F_1$ and $F_2$ .  Figure C.3 – OLT structure and signal wavelengths.  Figure C.4 – WDM filter response.  Figure D.1 – Single stage conventional ODN structure.  Figure D.2 – Multiple stage conventional ODN structure.  Figure D.3 – Implementation of coexistence PON systems.  Figure D.5 – Multiple-stage PtP WDM ODN structure.  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model.  Figure E.3 – Linear regression location for each measurement method.  Figure E.4 – Confidence band of the linear regression.  Figure E.5 – OTDR trace and noise.  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits.  Figure E.8 – Graphic representation of the amplification of the confidence interval.  Table 1 – Light source spectral requirements.  Table 2 – OTDR spectral requirements.  Table 2 – OTDR spectral requirements.  Table 2 – OTDR spectral requirements.  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.		·	
F.2.3 Pulse width. F.2.4 Averaging time F.2.5 Dead zone F.2.6 Distance sampling Bibliography.  Figure 1 – Single stage conventional ODN structure Figure 2 – Cabling configuration – Start and end of measured losses in reference test method Figure 3 – Typical OTDR schematic Figure 3 – Typical OTDR schematic Figure A.1 – One-cord reference measurement Figure A.2 – One-cord test measurement. Figure B.1 – Test measurement for method B Figure B.2 – Location of the connector ports of the cabling under test Figure B.3 – Graphic determination of F1 and F2 Figure C.1 – Location of the connector ports of the cabling under test Figure C.2 – Graphic determination of F1 and F2 Figure C.3 – OLT structure and signal wavelengths Figure D.1 – Single stage conventional ODN structure Figure D.2 – Multiple stage conventional ODN structure Figure D.3 – Implementation of coexistence PON systems Figure D.4 – Single-stage PIP WDM ODN structure Figure D.5 – Multiple-stage PIP WDM ODN structure Figure D.6 – Example of ODN structure for TWDM Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model. Figure E.3 – Linear regression location for each measurement method. Figure E.3 – Linear regression location for each measurement method. Figure E.5 – OTDR trace and noise Figure E.6 – Noise asymmetry function of DM. Figure E.7 – Measurement validity limits Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 2 – OTDR spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors		•	
F.2.4 Averaging time F.2.5 Dead zone F.2.6 Distance sampling Bibliography  Figure 1 - Single stage conventional ODN structure Figure 2 - Cabling configuration - Start and end of measured losses in reference test method  Figure 3 - Typical OTDR schematic Figure A.1 - One-cord reference measurement Figure A.2 - One-cord test measurement Figure B.1 - Test measurement for method B Figure B.3 - Graphic determination of $F_1$ and $F_2$ Figure B.3 - Graphic determination of $F_1$ and $F_2$ Figure C.1 - Location of the connector ports of the cabling under test Figure C.2 - Graphic determination of $F_1$ and $F_2$ Figure C.3 - OLT structure and signal wavelengths  Figure C.4 - WDM filter response Figure D.1 - Single stage conventional ODN structure  Figure D.2 - Multiple stage conventional ODN structure  Figure D.3 - Implementation of coexistence PON systems  Figure D.4 - Single-stage PIP WDM ODN structure  Figure D.5 - Multiple-stage PIP WDM ODN structure  Figure D.5 - Multiple-stage PIP WDM ODN structure  Figure E.1 - Observed PLC splitter wavelength dependency and mathematical model.  Figure E.3 - Linear regression location for each measurement method.  Figure E.3 - Linear regression location for each measurement method.  Figure E.5 - OTDR trace and noise  Figure E.6 - Noise asymmetry function of DM.  Figure E.7 - Measurement validity limits  Figure E.8 - Graphic representation of the amplification of the confidence interval  Table 1 - Light source spectral requirements.  Table 2 - OTDR spectral requirements  Table 2 - OTDR spectral requirements  Table 2 - OTDR spectral requirements  Table 3 - Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.			
F.2.5 Dead zone F.2.6 Distance sampling Bibliography.  Figure 1 - Single stage conventional ODN structure Figure 2 - Cabling configuration - Start and end of measured losses in reference test method Figure 3 - Typical OTDR schematic Figure 3 - Typical OTDR schematic Figure A.1 - One-cord reference measurement Figure B.1 - Test measurement for method B Figure B.2 - Location of the connector ports of the cabling under test Figure B.3 - Graphic determination of F1 and F2 Figure C.1 - Location of the connector ports of the cabling under test Figure C.3 - OLT structure and signal wavelengths Figure C.4 - WDM filter response Figure D.1 - Single stage conventional ODN structure Figure D.2 - Multiple stage conventional ODN structure Figure D.3 - Implementation of coexistence PON systems Figure D.4 - Single-stage PIP WDM ODN structure Figure D.5 - Multiple-stage PIP WDM ODN structure Figure D.6 - Example of ODN structure for TWDM Figure E.1 - Observed PLC splitter wavelength dependency and mathematical model Figure E.3 - Linear regression location for each measurement method Figure E.3 - Linear regression location for each measurement method Figure E.5 - OTDR trace and noise Figure E.6 - Noise asymmetry function of DM. Figure E.8 - Graphic representation of the amplification of the confidence interval  Table 4 - Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 2 - OTDR spectral requirements  Table 2 - OTDR spectral requirements  Table 3 - Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors			
Bibliography.  Figure 1 – Single stage conventional ODN structure.  Figure 2 – Cabling configuration – Start and end of measured losses in reference test method.  Figure 3 – Typical OTDR schematic.  Figure 3 – Typical OTDR schematic.  Figure A.1 – One-cord reference measurement  Figure A.2 – One-cord test measurement  Figure B.1 – Test measurement for method B.  Figure B.2 – Location of the connector ports of the cabling under test  Figure B.3 – Graphic determination of F1 and F2  Figure C.1 – Location of the connector ports of the cabling under test  Figure C.2 – Graphic determination of F1 and F2  Figure C.3 – OLT structure and signal wavelengths.  Figure C.4 – WDM filter response.  Figure D.1 – Single stage conventional ODN structure  Figure D.2 – Multiple stage conventional ODN structure  Figure D.3 – Implementation of coexistence PON systems.  Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM.  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector			
Bibliography.  Figure 1 – Single stage conventional ODN structure  Figure 2 – Cabling configuration – Start and end of measured losses in reference test method.  Figure 3 – Typical OTDR schematic.  Figure A.1 – One-cord reference measurement.  Figure A.2 – One-cord test measurement.  Figure B.1 – Test measurement for method B.  Figure B.3 – Graphic determination of F1 and F2  Figure B.3 – Graphic determination of F1 and F2  Figure C.1 – Location of the connector ports of the cabling under test.  Figure C.2 – Graphic determination of F1 and F2  Figure C.3 – OLT structure and signal wavelengths.  Figure C.4 – WDM filter response.  Figure D.1 – Single stage conventional ODN structure.  Figure D.2 – Multiple stage conventional ODN structure.  Figure D.3 – Implementation of coexistence PON systems.  Figure D.5 – Multiple-stage PIP WDM ODN structure.  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model.  Figure E.2 – Spectral attenuation.  Figure E.3 – Linear regression location for each measurement method.  Figure E.5 – OTDR trace and noise.  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits.  Figure E.8 – Graphic representation of the amplification of the confidence interval.  Table 1 – Light source spectral requirements.  Table 2 – OTDR spectral requirements.  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors.			
Figure 1 – Single stage conventional ODN structure  Figure 2 – Cabling configuration – Start and end of measured losses in reference test method  Figure 3 – Typical OTDR schematic  Figure A.1 – One-cord reference measurement	_		
Figure 2 — Cabling configuration — Start and end of measured losses in reference test method  Figure 3 — Typical OTDR schematic  Figure A.1 — One-cord reference measurement	Dibilography:		
Figure 2 — Cabling configuration — Start and end of measured losses in reference test method  Figure 3 — Typical OTDR schematic  Figure A.1 — One-cord reference measurement	Figure 1 _ Si	nale stage conventional ODN structure	13
Figure A.1 — One-cord reference measurement	_		10
Figure A.1 – One-cord reference measurement			14
Figure A.1 – One-cord reference measurement	Figure 3 – Ty	/pical OTDR schematic	16
Figure A.2 — One-cord test measurement			
Figure B.1 – Test measurement for method B	•		
Figure B.2 – Location of the connector ports of the cabling under test  Figure B.3 – Graphic determination of $F_1$ and $F_2$	_		
Figure B.3 – Graphic determination of $F_1$ and $F_2$	_		
Figure C.1 – Location of the connector ports of the cabling under test  Figure C.2 – Graphic determination of $F_1$ and $F_2$	_		
Figure C.2 – Graphic determination of F1 and F2  Figure C.3 – OLT structure and signal wavelengths  Figure C.4 – WDM filter response  Figure D.1 – Single stage conventional ODN structure  Figure D.2 – Multiple stage conventional ODN structure  Figure D.3 – Implementation of coexistence PON systems  Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors.			
Figure C.3 – OLT structure and signal wavelengths  Figure C.4 – WDM filter response  Figure D.1 – Single stage conventional ODN structure  Figure D.2 – Multiple stage conventional ODN structure  Figure D.3 – Implementation of coexistence PON systems  Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors			
Figure C.4 – WDM filter response  Figure D.1 – Single stage conventional ODN structure  Figure D.2 – Multiple stage conventional ODN structure  Figure D.3 – Implementation of coexistence PON systems  Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors			
Figure D.1 – Single stage conventional ODN structure	_	-	
Figure D.2 – Multiple stage conventional ODN structure Figure D.3 – Implementation of coexistence PON systems Figure D.4 – Single-stage PtP WDM ODN structure Figure D.5 – Multiple-stage PtP WDM ODN structure Figure D.6 – Example of ODN structure for TWDM Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model Figure E.2 – Spectral attenuation Figure E.3 – Linear regression location for each measurement method Figure E.4 – Confidence band of the linear regression Figure E.5 – OTDR trace and noise Figure E.6 – Noise asymmetry function of DM. Figure E.7 – Measurement validity limits Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements Table 2 – OTDR spectral requirements Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	-	· DIDI LIVILO 01200 7 3.2022	
Figure D.3 – Implementation of coexistence PON systems  Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors			
Figure D.4 – Single-stage PtP WDM ODN structure  Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector.  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors.	Figure D.2 –	Multiple stage conventional ODN structure	34
Figure D.5 – Multiple-stage PtP WDM ODN structure  Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model  Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	Figure D.3 –	Implementation of coexistence PON systems	34
Figure D.6 – Example of ODN structure for TWDM  Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model	Figure D.4 –	Single-stage PtP WDM ODN structure	35
Figure E.1 – Observed PLC splitter wavelength dependency and mathematical model	Figure D.5 –	Multiple-stage PtP WDM ODN structure	36
Figure E.2 – Spectral attenuation  Figure E.3 – Linear regression location for each measurement method  Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	Figure D.6 –	Example of ODN structure for TWDM	36
Figure E.3 – Linear regression location for each measurement method	Figure E.1 –	Observed PLC splitter wavelength dependency and mathematical model	40
Figure E.4 – Confidence band of the linear regression  Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM.  Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	Figure E.2 –	Spectral attenuation	40
Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM	Figure E.3 –	Linear regression location for each measurement method	42
Figure E.5 – OTDR trace and noise  Figure E.6 – Noise asymmetry function of DM	Figure E.4 –	Confidence band of the linear regression	43
Figure E.6 – Noise asymmetry function of <i>DM</i> Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	· ·	· · · · · · · · · · · · · · · · · · ·	
Figure E.7 – Measurement validity limits  Figure E.8 – Graphic representation of the amplification of the confidence interval  Table 1 – Light source spectral requirements  Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	•		
Figure E.8 – Graphic representation of the amplification of the confidence interval	_	·	
Table 1 – Light source spectral requirements	•	•	
Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	r iguro E.o	Crapino representation of the amplification of the confidence interval	
Table 2 – OTDR spectral requirements  Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	Table 1 – Lio	tht source spectral requirements	15
Table 3 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using the same photodetector  Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors	_	•	
same photodetector			17
Table 4 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using different photodetectors			18
photodetectors	-		
Table 5 – Uncertainty for a given attenuation at 1 310 nm and 1 550 nm using OTDR		· · · · · · · · · · · · · · · · · · ·	18
	Table 5 – Un	certainty for a given attenuation at 1 310 nm and 1 550 nm using OTDR	19

IFC.	61280.	4-3-2022	@ IFC	2022

	_	
_	ວ	_

Table C.1 – Uncertainty for a given attenuation at 1 625 nm and 1 650 nm using OTDR	31
Table E.1 – Uncertainties due to measuring instruments	38
Table E.2 – Uncertainties due to the setup	38
Table E.3 – Uncertainties due to cabling	39
Table E.4 – Difference of attenuation coefficient	41
Table F 5 – Sensitivity coefficients	49

# iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST EN IEC 61280-4-3:2022

https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sisten-iec-61280-4-3-2022

### INTERNATIONAL ELECTROTECHNICAL COMMISSION

#### FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES -

### Part 4-3: Installed passive optical networks – Attenuation and optical return loss measurements

#### **FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

IEC 61280-4-3 has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics. It is an International Standard.

This publication contains an attached file titled "Supplemental Data" in the form of an Excel spread sheet. This file is intended to be used as a complement and does not form an integral part of the standard.

The text of this International Standard is based on the following documents:

Draft	Report on voting
86C/1749A/CDV	86C/1787/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

IEC 61280-4-3:2022 © IEC 2022

**-7-**

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at <a href="https://www.iec.ch/members\_experts/refdocs">www.iec.ch/members\_experts/refdocs</a>. The main document types developed by IEC are described in greater detail at <a href="https://www.iec.ch/publications">www.iec.ch/publications</a>.

A list of all parts in the IEC 61280 series, published under the general title *Fibre optic communication subsystem test procedures*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The "colour inside" logo on the cover page of this document indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

standards.iteh.ai

SIST EN IEC 61280-4-3:2022 https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sist

IEC 61280-4-3:2022 © IEC 2022

### INTRODUCTION

IEC has developed a large set of standards for measurement of fibre optic cable plants. These standards are applicable to passive optical networks (PONs) if specifics of these networks are known and understood. This document provides dedicated procedures for attenuation measurements in PONs as well as additional information.

For the purpose of this document, a PON is a point-to-multipoint network that includes optical line terminals (OLTs), optical network terminals (ONTs), and an optical fibre infrastructure that is entirely passive and is represented by a single-rooted point-to-multipoint tree of optical fibres with splitters, combiners, filters, and other passive components.

PONs are commonly used in fibre-to-the-home (FTTH) and fibre-to-the-building (FTTB) optical access networks (OAN). In addition, the measurement principles described in this document may also apply to PONs used in other applications, like passive optical local area networks (PO-LANs).

## iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>SIST EN IEC 61280-4-3:2022</u> https://standards.iteh.ai/catalog/standards/sist/6c1e701f-ca79-4778-b16f-e77db65dcfa4/sisten-iec-61280-4-3-2022

- 8 -

### FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES -

### Part 4-3: Installed passive optical networks – Attenuation and optical return loss measurements

### 1 Scope

This part of IEC 61280 describes the measurement of attenuation, optical return loss and optical power in installed passive optical networks (PONs) using single-mode fibre.

This document specifies two methods for measuring the attenuation before activation of the PON:

- method A: one-cord method using a light source and a power meter (LSPM);
- method B: optical time-domain reflectometer (OTDR) method in upstream direction only, with reduction of uncertainties due to the variation of backscatter coefficient.

In addition, method C, which is described in informative Annex C, provides an estimate of the attenuation after partial activation of the PON by using a U band filtered optical time-domain reflectometer (FOTDR) in an upstream direction.

### 2 Normative references standards.iteh.ai

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60793-2-50, Optical fibres – Part 2-50: Product specifications – Sectional specification for class B single-mode fibres

IEC 61280-1-3, Fibre-optic communication subsystem test procedures – Part 1-3: General communication subsystems – Measurement of central wavelength, spectral width and additional spectral characteristics

IEC 61280-4-2, Fibre-optic communication subsystem test procedures – Part 4-2: Installed cable plant – Single-mode attenuation and optical return loss measurement

IEC TR 61282-14:2019, Fibre optic communication system design guidelines – Part 14: Determination of the uncertainties of attenuation measurements in fibre plants

IEC 61300-3-35, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-35: Examinations and measurements – Visual inspection of fibre optic connectors and fibre-stub transceivers

IEC 61315, Calibration of fibre-optic power meters

IEC 61746-1:2009, Calibration of optical time-domain reflectometers (OTDR) – Part 1: OTDR for single-mode fibres

IEC 61753-031-2, Fibre optic interconnecting devices and passive components – Performance standard – Part 031-2: Non-connectorized single-mode 1  $\times$  N and 2  $\times$  N non-wavelength-selective branching devices for Category C – Controlled environment